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ERRATUM

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Erratum to: Analysis of velocity-mapped ion images from high-resolution crossed-beam scattering experiments: a tutorial review

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Erratum

Unfortunately, the original version of this article [1] contained an error. The DOI was included incorrectly in the PDF version of the file. The DOI has now been corrected in the original PDF and is also included correctly below:

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1. Zastrow V et al. Analysis of velocity-mapped ion images from high-resolution crossed-beam scattering experiments: a tutorial review. *EPJ Tech Instrum.* 2015;2:11.

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